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February 18, 2004

Commissioner for Patents

P.O.Box 1450

Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572

28 Davis Avenue

Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/723,237 11/26/03

Chih-Ta Wu et al.

A METHOD TO FORM A ROBUST TiCl4 BASED CVD TiN FILM

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation In An Application.

The following Patents and/or Publications are submitted to comply with the duty of disclosure under CFR 1.97-1.99 and 37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on February ? 3, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

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- U.S. Patent 6,297,147 to Yang et al., "Plasma Treatment for Ex-situ Contact Fill," discloses a method for removing oxygen from the surface of an oxidized metal layer prior to depositing a subsequent metal layer.
- U.S. Patent 5,970,378 to Shue et al., "Multi-step Plasma
 Treatment Process for Forming Low Resistance Titanium Nitride
 Layer," discusses a method for forming a titanium nitride layer
 within an integrated circuit.

The following two U.S. Patents describe forming a multilayer TiN film comprised of a least two TiN layers on a TiN underlayer:

- 1) U.S. Patent 6,207,557 to Lee et al., "Method of Forming Multilayer Titanium Nitride Film by Multiple Step Chemical Vapor Deposition Process and Method of Manufacturing Semiconductor Device Using the Same."
- 2) U.S. Patent 6,291,342 to Lee et al., "Methods of Forming Titanium Nitride Composite Layers Using Composite Gases having Increasing TiCl4 to NH3 Ratios."

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U.S. Patent 6,140,223 to Kim et al., "Methods of Forming Contacts for Integrated Circuits Using Chemical Vapor Deposition and Physical Vapor Deposition," discusses a TiN glue layer formed in a contact hole in three steps.

Sincerely,

Stephen B. Ackerman,

Reg. No. 37761

INFO	INFORMATION DISCLOSURE CITATION								TSMC-01-(630 10/723,23			
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